Picture-Frame Characterization and Defect Analysis in LSSTCam

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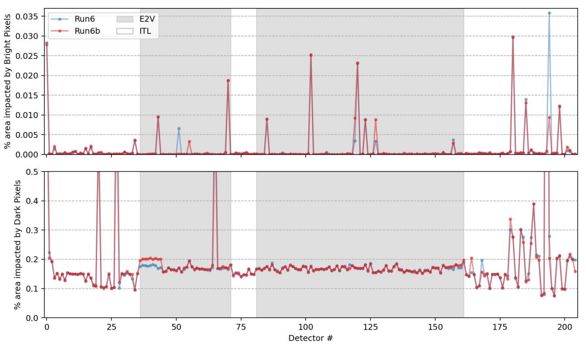
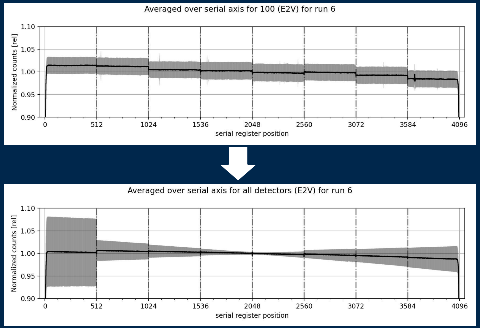
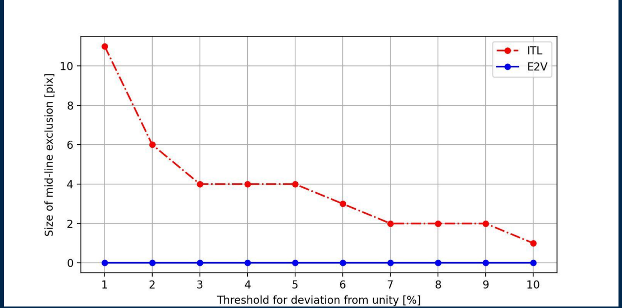
Defect Masks



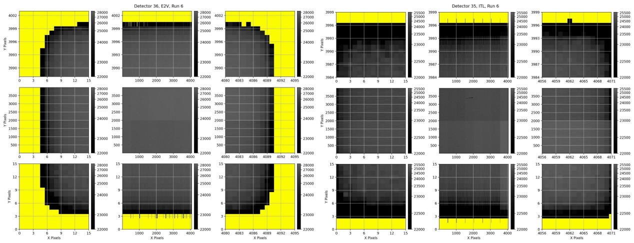
Combining Like Detectors



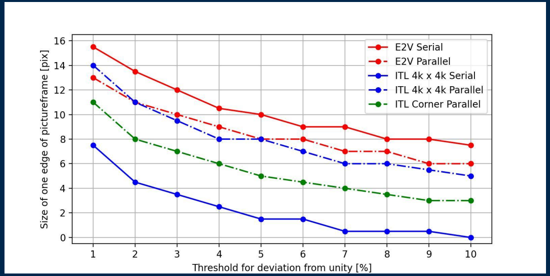
Midline Bloom



Picture-Frames



Edge Roll-Off



Results

- Different detectors types have different sensor edge effects
- Use results to inform an ISR mask for processed images
- Future study of bright and dark defects
- Extend this study to include vignetting, and study individual detectors edge and midline bloom